

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/581,593	MIYOSHI ET AL.	
Examiner	Art Unit	

1725

Len Tran

	SEARCHED					
Class	Subclass	Date	Examiner			
422	139	12/1/2004	LT			
	141					
	142					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
422	all above	12/1/2004	LT		
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